

PTO/SB/08A (08-03)
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Substitute for form 1449/PTO

Sheet 1

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

	Cor	mplete if Known
	Application Number	10/799838
	Filing Date	Mar 12, 2004
	First Named Inventor	Randy Hoffman
	Art Unit	2814
	Examiner Name	Long Pham
-	Attomey Docket Number	200316548-1

			U. S. PATENT	DOCUMENTS	
Examiner Initials*	Cite No.1	Document Number Number-Kind Code ^{2 (F known)}	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevan Figures Appear
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		•	OTHER REF	ERENCES (includ	ing Au	ıthor, Title, Date, P	Pertine	ent Pages, etc.)		
_ Lf)	10	Aoki, Akira, e	t al., "Tin Oxide Th	nin Film	n Transistors", Japan	J. Ap	pl. Phys., Vol. 9,	p.582 (1970).	
	(1R	Carcia, P.F., e Applied Physic	t al., "Transparent cs Letters, Vol. 82	ZnO t , No. 7	hin-film transistor fab , pp. 1117-1119 (Fel	oricate bruary	d by rf magnetron 17, 2003).	sputtering",	
	/	15	Carcia, P.F., e Proc., Vol. 76	nt al., "ZnO Thin Fi 9, pp. H72.1-H72.	lm Trai .6 (200	nsistors for Flexible E 3).	Electroi	nics", Mat. Res. S	oc. Symp.	
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		OTHER REFE	RENCES (includin	g Au	thor, Title, Date, P	ertin	ent Pages, etc.)		
LP	20	Fu, Shelton, et 520-527.	al., "MOS and MO	SFET	with Transistion Me	tal Ox	kides", SPIE Vol. 2		
	2R	Giesbers, J.B., Microeletronic	et al., "Dry Etching Engineering, Vol. 3	of Al 5, pp.	II-Oxide Transparent 71-74 (1997).	Thin	Film Memory Tran	nsistors",	
	28	Grosse-Holz, K Symp. Proc., \	.O., et al. "Semicor /ol. 401, pp. 67-72	nduction (1996	ve Behavior of Sb D 3).	oped	SnO2 Thin Films"	, Mat. Res. S	Soc.
EXAMIN	NER	Long	Pham		DATE CONSIDER	RED	12/6/0	N .	

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LP	30	Hoffman, R.L., 82, No. 5, pp.	et al., "ZnO-based 733-735 (February	trans 3, 20	parent thin-film transi 003).	istors	", Applied Physic	s Letters, Vo	I.
	3R	Masuda, Satos and their elect (February 1, 2	rical properties", Jo	rent t	hin film transistors us of Applied Physics, V	sing Zi Vol. 9	nO as an active c 3, No. 3, pp. 162	hannel layer 24-1630	
	38	Nishi, Junya, e Appl. Phys., V	ot al., "High Mobility ol. 42, Part 2, No.	y Thir 4A, p	n Film Transistors with p. L347-L349 (April,	h Trar 2003	nsparent ZnO Cha	annels", Jpn.	J.
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LP	40	Ohya, Yutaka, Jpn. J. Appl. f	et al., "Thin Film ī Phys., Vol. 40, Pari	Fransis t 1, No	stor of ZnO Fabricates 5. 1, pp. 297-298 (Ja	d by C anuary	Chemical Solution 7, 2001).	Deposition"	,	
	4R	Pallecchi, llaria Physics Letters	, et al. "SrTIO3-ba s, Vol. 78, No. 15,	sed m	etal-insulator-semico 244-2246 (April 9, 2	nducte (001).	or heterostructure	es" Applied		
	45	Prins, M. W. J No. 25, pp. 36	., et al., "A ferroel 550-3652 (June 17	ectric 7, 199	transparent thin-film 8).	transi	stor", Appl. Phys	. Lett., Vol.	68,	
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	50				and device behavior i		<u></u>		vs.		
LP		Lett., Vol. 68,	No. 19, pp. 2660	-2662	(May 6, 1996).						
	5R	Uneno, K., et a Physics Letters	ıl. "Field-effect tra , Vol. 83, No. 9, _I	nsistor pp. 17!	on SrTiO3 with sput 55-1757 (September	ttered Al.	203 gate insul).	lator", Applie	e d		
	58	channel, a pos	irgen, et al., "An i sible new gas sens p. 471-474 (Septe	sor dev	ed gate thin-film transice" The 11th Europ 21-24, 1997).	sistor us pean Con	ing SnO2 as so ference on Sol	emiconductin id State	g		
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LP	60	Yoshida, A., " Transactions o	Three Terminal Field on Applied Supercon	d Effective	t Superconducting C rity, Vol. 5, No. 2, p	Device op. 289	Using SrTiO3 Ch 2-2895 (June, 1	nannel" IEEE 995).		
	6R	Solid-State Ele	ctronics, Vol. 7, Pe	rgamo	n Press, Notes pp. 7	701-70	2 (1964).			
Anonymous, "Transparent and/or mer Disclosure, p. 890 (July 1998).					ory thin film transisto	ors in L	CD's and PLEAC)_" Research		
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